

Notice of References Cited	Application/Control No. 09/763,365	Applicant(s)/Patent Under Reexamination TAKIZAWA ET AL.
	Examiner David L. Hogans	Art Unit 2813

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
A	US-6,124,614		09-2000	Ryum et al.	257/347
B	US-				
C	US-				
D	US-				
E	US-				
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J	US-				
K	US-				
L	US-				
M	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N						
O						
P						
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R						
S						
T						

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
U	Quirk et al., Semiconductor Manufacturing Technology (2001), Prentice Hall, pages 309-311.	
V		
W		
X		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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